

Notice of References Cited

Application/Control No.

10/588,537

Applicant(s)/Patent Under
Reexamination
HIGASHIDA ET AL.

Examiner

ANDREW OH

Art Unit

2466

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0026240 A1	02-2003	Eyuboglu et al.	370/349
*	B	US-2003/0177267 A1	09-2003	Orava et al.	709/245
*	C	US-2004/0073612 A1	04-2004	Kim et al.	709/205
*	D	US-2004/0158872 A1	08-2004	Kobayashi, Naofumi	725/120
*	E	US-2004/0221042 A1	11-2004	Meier, Robert C.	709/227
*	F	US-2006/0165107 A1	07-2006	Legallais et al.	370/401
*	G	US-2006/0154603 A1	07-2006	Sachs et al.	455/039
*	H	US-7,280,495 B1	10-2007	Zweig et al.	370/312
*	I	US-7,627,690 B2	12-2009	Kobayashi, Naofumi	709/238
*	J	US-2001/0018714	08-2001	Yagyu et al.	709/245
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1679855 A1	07-2006	European Patent	BORDES et al.	H04L 12/18
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.